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Form PTO-1449 (Substitute)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	Attorney Docket Number LAZE-01015US1	Serial/Patent Number 10/684,760
		Applicant/Patent Owner Thomas F. Rust	
		Filing/Issue Date October 14, 2003	Group Art Unit 3681 3708

Information Disclosure Statement
BY APPLICANT
(Use several sheets if necessary)

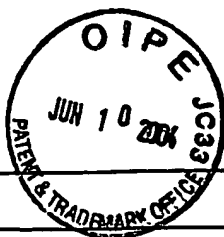
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<i>U</i>	2	4,575,822	03/11/86	Quate	365	174	02/15/83
	3	4,829,507	05/09/89	Kazan et al.	369	126	08/15/88
	4	4,831,614	05/16/89	Duerig et al.	369	101	03/13/87
	5	4,916,688	04/10/90	Foster et al.	369	126	03/31/88
	6	4,945,515	07/31/90	Ooumi et al.	365	174	09/12/88
	7	4,962,480	10/09/90	Ooumi et al.	365	151	09/12/88
	8	4,987,312	01/22/91	Eigler	250	492.3	11/07/89
	9	5,038,322	08/06/91	Van Loenen	365	114	02/03/89
	10	5,043,578	08/27/91	Guethner et al.	250	307	04/05/90
	11	5,051,977	09/24/91	Goldberg	369	126	08/30/89
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	13	5,095,479	03/10/92	Harigaya et al.	369	288	08/12/91
	14	5,097,443	03/17/92	Kaneko et al.	365	153	03/28/90
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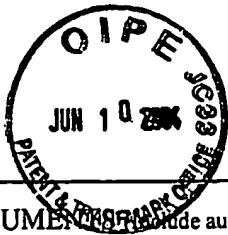
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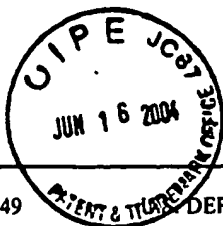


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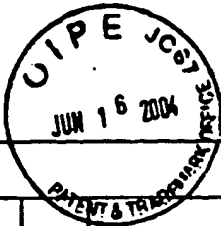
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